

**APPENDIX 3: Photographs of test setup**

**Conducted Emission**



**Photo 1**



**Photo 2**

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**UL Japan, Inc.**

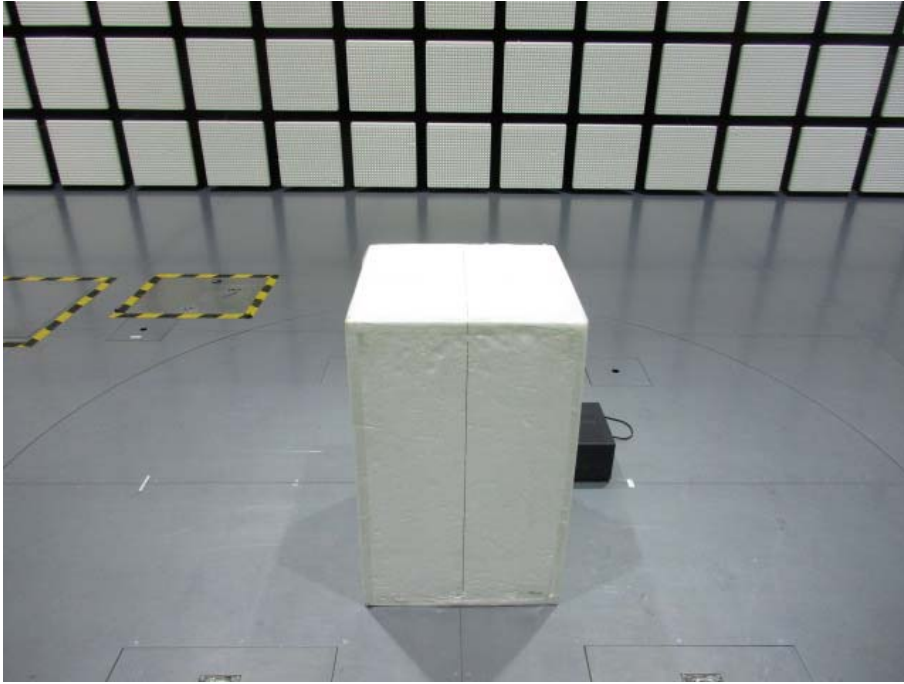
**Kashima EMC Lab.**

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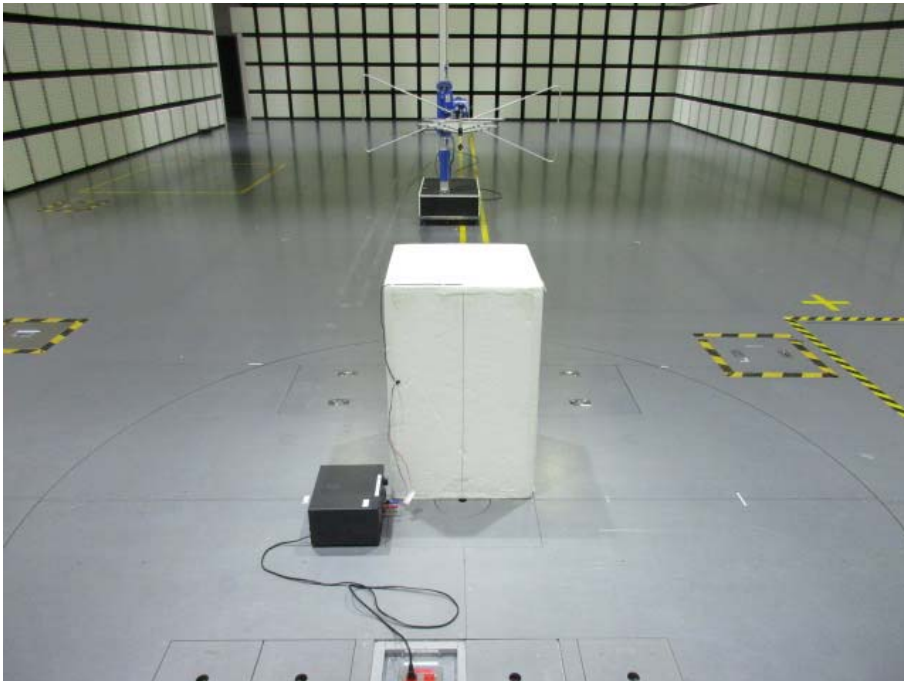
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### Radiated Spurious Emission



**Photo 1**



**Photo 2**

### Radiated Spurious Emission



Photo 1

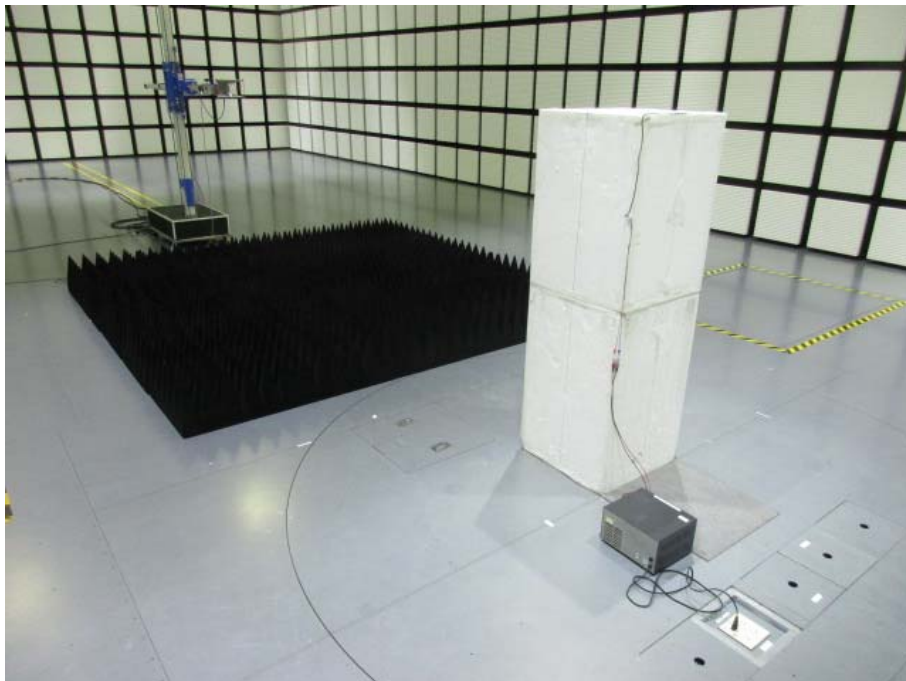
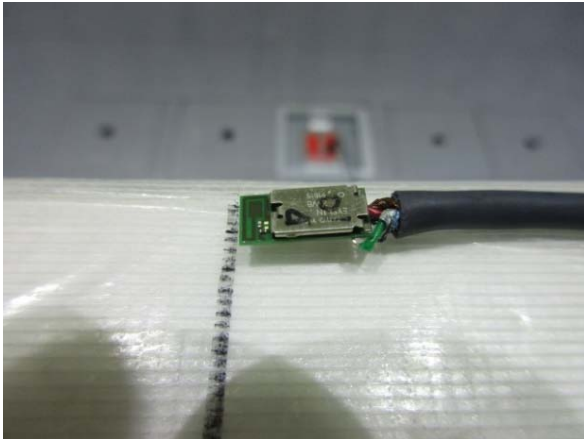


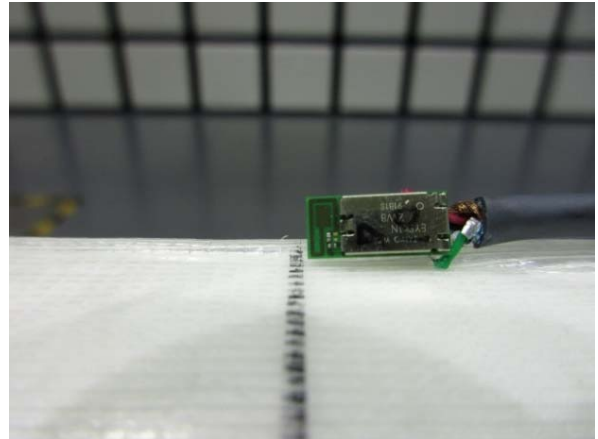
Photo 2

**Worst Case Position**

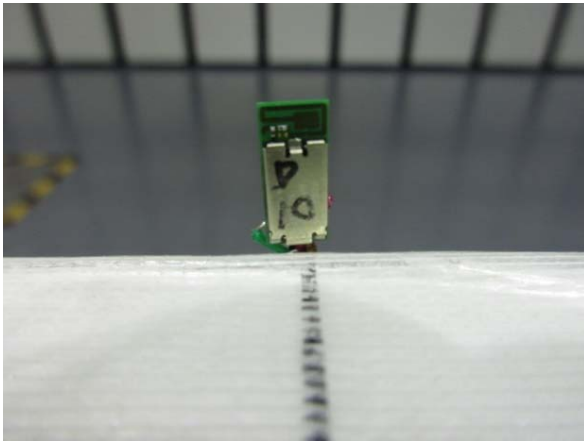
**X-axis**



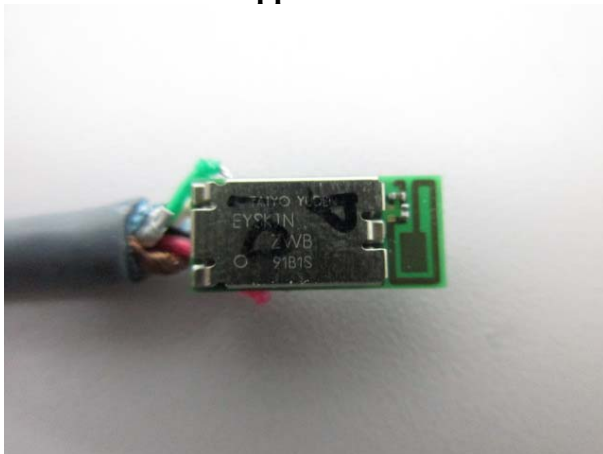
**Y-axis**



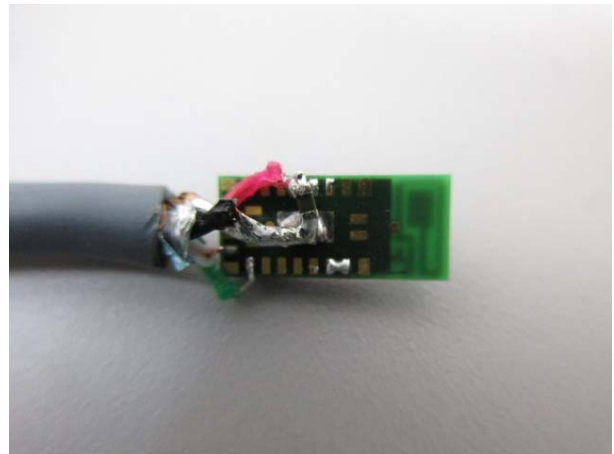
**Z-axis**



**Upper side**



**Back side**



\*The chip is mounted to the EUT as a part of a test jig.

**End of Report**

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